

Contract beamline

- Contents of experiment reports

	<i>title</i>	<i>proposal no.</i>	<i>first author</i>	<i>page</i>
BL16XU				
	X-ray Diffraction of Co alloy magnetic film	C99B16XU-300N	T.Hirose	243
	The Crystal Structure Analysis of Lithium Oxide	C99B16XU-301N	K.Yamaura	244
	X-ray Scattering Study on the Structure of Ultra-thin Insulator Films	C99B16XU-302N	M.Takahashi	245
	X-ray Diffraction Measurements for Thin Films of (BaSr)TiO ₃ /Si and Other Materials	C99B16XU-303N	S.Kimura	246
	Crystallographic characterization of high-strength steel wire	C99B16XU-304N	K.Yamaguchi	247
	XRD studies on a LiNiO ₂ secondary battery utilized anomalous scattering	C99B16XU-305N	I.Konomi	248
	Structure Analysis of Thin Oxide Film Formed on Pure Iron Surface	C99B16XU-306N	K.Ikeda	249
	Peak Separation of In-plane Diffraction Patterns from Cu/NiFe Thin Film using Anomalous Dispersion Effect	C99B16XU-307N	K.Ueda	250
	X-ray fluorescence of magnetic metal films	C99B16XU-308N	N.Awaji	251
	Total Reflection X-ray Analysis of ruthenium on a silicon wafer by using wavelength-dispersive method	C99B16XU-310N	K.Ogata	252
	Measurements of Submicron Lateral Resolution using Focused X-rays	C99B16XU-311N	Y.Hirai	253
	Micro-analysis of Water-Tree in Cross-linked Polyethylene	C99B16XU-311N	T.Yamazaki	254
	Diffraction Microscopy with an X-ray Microbeam	C99B16XU-311N	M.Hasegawa	255
	Structural Analysis of Iron Oxide (Rust) Layer of Mild Steel by SR-XRD	C99B16XU-312N	T.Nakayama	256
	The Analysis of Very Small Quantity Impurities on Silicon Wafer	C99B16XU-313N	K.Liu	257

Analysis of Surface Impurities on Semiconductor Wafers	C99B16XU-314N	S.Ozaki	258
In-situ X-ray diffraction study of crystallization process of GeSbTe thin films during heat treatment	C99B16XU-315N	I.Konomi	259
Structure Analysis of CoPt ₃ Using Anomalous X-ray Scattering	C99B16XU-316N	H.Deguchi	260

BL16B2

Local Structure Analysis on (Y ₂ O ₃)X(ZrO ₂) _{1-x} and La _{0.7} Sr _{0.3} MnO ₃ by Transmission XAFS	C99B16B2-400N	S.Ozaki	261
Structure Analyses of Electronic Materials :GaAs wafers and Amorphous SiN _x Films on GaAs	C99B16B2-401N	K.Haga	262
XAFS study of Barium Strontium Titanate	C99B16B2-402N	Y.Uehara	263
An in situ XAFS Study on Lithium-ion Batteries using LiNiO ₂ Cathode	C99B16B2-403N	T.Okamoto	264
The Structure Analysis of Lithium Oxide by XAFS Method	C99B16B2-404N	A.Yamada	265
Absolute Measurement of the Energy of X-ray Absorption Edge for Copper	C99B16B2-405N	T.Watanabe	266
Study of the local structures of electrode materials for chemical batteries	C99B16B2-406N	J.Hirose	267
XAFS Measurements of Pt fine particles	C99B16B2-407N	H.Teranishi	268
Analysis of Microstructure of Iron Corrosion Products by SR-XAFS	C99B16B2-408N	T.Nakayama	269
Ta L-shell XAFS measurements of tantalum oxide films	C99B16B2-409N	M.Takemura	270
Local Structure Analysis of Perovskite and Fluorite Oxides for Solid Oxide Fuel Cell	C99B16B2-410N	H.Deguchi	271
X-ray reflectivity study of Silicon Oxides and Nitrides thin films	C99B16B2-411N	Y.Uehara	272
X-ray Reflectivity of Diamond-like Carbon Thin Films	C99B16B2-412N	N.Okuda	273

X-ray diffraction study of magnetic metal films	C99B16B2-413N	S.Takeishi	274
Valency of Co Ion in Sr Ferrite	C99B16B2-416N	H.Kubota	275
XAFS Study on Local Structure of Ce and Zr in Industrial Catalysts -1-	C99B16B2-417N	Y.Nagai	276
The Structure Analysis of GaN by XAFS Method	C99B16B2-418N	T.Miyajima	277

BL24XU

X-ray Structure Analyses of Isoamylase and Related Enzymes	C99B24XU-501N	Y.Katsuya	278
Evaluation of Biocrystallography Experimental Hutch of Hyogo Beamline (BL24XU)	C99B24XU-502N	Y.Katsuya	279
Effects of amino acids and chirality for molecular folding of desoxazoline-ascidiacyclamide derivatives : Part 1. Structure of alanine derivative, <i>cyclo</i> (-Ala-a Thr-D-Val-Thz-Ile-a Thr-D-Val-Thz)	C99B24XU-503N	A.Asano	280
X-Ray structure analysis of human initiation factor 4E	C99B24XU-504N	T.Ishida	281
Study on the Mechanism of Thermostability of Enzymes and Proteins	C99B24XU-506N	K.Harata	282
Crystallographic analysis of proteins related to drug-design I	C99B24XU-507N	S.Misaki	283
Crystallographic analysis of functional organic micro crystals	C99B24XU-509N	K.Yanagi	284
Crystallographic analysis of helicase from E.coli	C99B24XU-514N	H.Hiramatsu	285
Crystallographic analysis of complex crystal of serine protease inhibitor	C99B24XU-518N	M.Koizumi	286
Crystal Structure of Full-Length Ser/Thr Protein Kinase	C99B24XU-519N	M.Aoki	287
Crystallographic Study of <i>Thermus thermophilus</i> RuvB	C99B24XU-523N	N.Kunishima	288
Crystallographic analysis of Serin Protease Inhibitor	C99B24XU-528N	M.Kamimura	289

Local structural analysis of TiAlN films	C99B24XU-531N	T.Kaneyoshi	290
Grazing Incidence X-ray Diffraction of $(\sqrt{3}x\sqrt{3})R30^\circ$ -B on Si(111) Substrate	C99B24XU-532N	T.Kawamura	291
Some Observations on the Surface Structure of Ion Implanted Molds for Rubber	C99B24XU-535N	S.Nakagawa	292
ROCKING CURVE MEASUREMENT OF INFRARED LEDS USING HIGHLY PARALLEL X-RAY MICROBEAM	C99B24XU-541N	S.Takeda	293
Formation of X-Ray Microbeam Using Ta Phase Zone Plate and Its Application to Scanning X-Ray Microscope-II	C99B24XU-542N	Y.Kagoshima	294
Measurements of characteristics of multilayer supermirrors	C99B24XU-543N	K.Tamura	295
Observation of Cracks and Voids in Structural Materials by Refraction Contrast X-ray Imaging	C99B24XU-544N	T.Nakayama	296
High-resolution microbeam x-ray diffractometry applied to narrow-stripe selective MOVPE grown InGaAsP/InP layers	C99B24XU-545N	S.Kimura	297
Real time phase-contrast imaging study for electronic double-layer capacitor (EDLC)	C99B24XU-546N	K.Kobayashi	298
Characterization of the surfaces of silicon wafers by the grazing incidence X-ray diffraction topography and the reflectivity measurements	C99B24XU-547N	T.Katoh	299
Measurements of projection images for micro-tomography	C99B24XU-548N	K.Tani	300
Characterization of Subsurface Microstructure and Microcrack for Metallic Materials	C99B24XU-549N	O.Umezawa	301
Phase-Contrast X-Ray Imaging of Trace Forensic Samples Using Horizontally Expanded Synchrotron Radiation X-Rays with Asymmetric Bragg Reflection	C99B24XU-550N	T.Ninomiya	302
X-Ray Refractive Lenses for Microbeam Technology	C99B24XU-551N	Y.Zhang	303
X-ray refraction contrast imaging of internal structure of power transmission belt	C99B24XU-552N	Y.Matsui	304
Detection of peripheral type lung cancer of nude mice with Synchrotron Radiation and Au-NPe6	C99B24XU-553N	K.Aizawa	305
Development of X-Ray Imaging Using High Brilliance Undulator Synchrotron Radiation	C99B24XU-554N	M.Ando	306
Synchrotron Radiation-Xray Studies of Improvement on SiC Single Crystal	C99B24XU-555N	K.Tanino	307